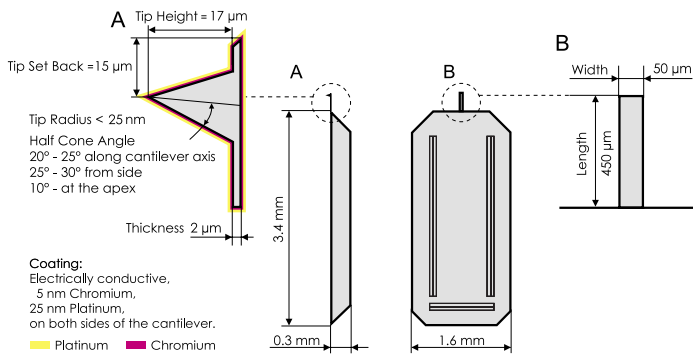




AFM probe Model: *ElectriCont-G*



- Contact Mode and Electric Modes like:
 - Scanning Capacitance Microscopy (SCM)
 - Electrostatic Force Microscopy (EFM)
 - Kelvin probe Force Microscopy (KFM)
 - Scanning probe lithography
- Rotated Monolithic Silicon Probe
 - Symmetric Tip Shape
 - Chipsize: 3.4 x 1.6 x 0.3 mm
 - Alignment Grooves
- Coating: Electrically conductive coating of 5 nm Chromium and 25 nm Platinum on both sides of the cantilever. This coating also enhances the laser reflectivity of the cantilever
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	13 kHz	+/- 4 kHz
Force Constant	0.2 N/m	0.07 - 0.4 N/m
Cantilever Length	450 μm	+/- 10 μm
Mean Width	50 μm	+/- 5 μm
Thickness	2 μm	+/- 1 μm
Tip Height	17 μm	+/- 2 μm
Tip Set Back	15 μm	+/- 5 μm
Tip Radius	< 25 nm	
Coating	Cr/Pt on both sides	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	
Contact Resistance	300 Ohms on platinum thin film surface	

Order Code	Units in Package	Coating	Price
ContE-G-10	10 pieces	Cr/Pt	\$240
ContE-G-50	50 pieces	Cr/Pt	\$1000